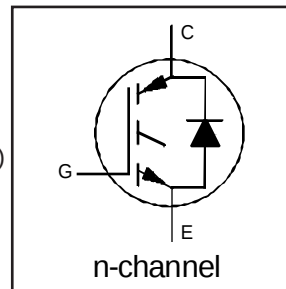


INSULATED GATE BIPOLAR TRANSISTOR
WITH ULTRAFAST SOFT RECOVERY DIODE

Short Circuit Rated
UltraFast CoPack IGBT

Features

- Short circuit rated -10 μ s @125°C, $V_{GE} = 15V$
- Switching-loss rating includes all "tail" losses
- HEXFRED™ soft ultrafast diodes
- Optimized for high operating frequency (over 5kHz)
See Fig. 1 for Current vs. Frequency curve

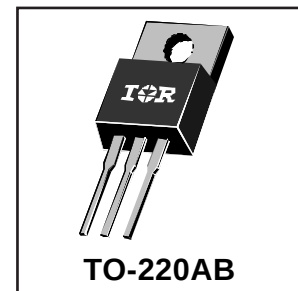


$V_{CES} = 600V$
$V_{CE(sat)} \leq 3.8V$
@ $V_{GE} = 15V$, $I_C = 14A$

Description

Co-packaged IGBTs are a natural extension of International Rectifier's well known IGBT line. They provide the convenience of an IGBT and an ultrafast recovery diode in one package, resulting in substantial benefits to a host of high-voltage, high-current, applications.

These new short circuit rated devices are especially suited for motor control and other applications requiring short circuit withstand capability.



Absolute Maximum Ratings

	Parameter	Max.	Units
V_{CES}	Collector-to-Emitter Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	23	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	14	
I_{CM}	Pulsed Collector Current ①	46	
I_{LM}	Clamped Inductive Load Current ②	46	
$I_F @ T_C = 100^\circ C$	Diode Continuous Forward Current	12	
I_{FM}	Diode Maximum Forward Current	46	
t_{sc}	Short Circuit Withstand Time	10	μs
V_{GE}	Gate-to-Emitter Voltage	± 20	V
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	100	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	42	
T_J	Operating Junction and	-55 to +150	$^\circ C$
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)	
	Mounting Torque, 6-32 or M3 Screw.	10 lbf•in (1.1 N•m)	

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case - IGBT	-----	-----	1.2	$^\circ C/W$
$R_{\theta JC}$	Junction-to-Case - Diode	-----	-----	2.5	
$R_{\theta CS}$	Case-to-Sink, flat, greased surface	-----	0.50	-----	
$R_{\theta JA}$	Junction-to-Ambient, typical socket mount	-----	-----	80	
Wt	Weight	-----	2 (0.07)	-----	g (oz)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	600	----	----	V	$V_{GE} = 0V, I_C = 250\mu A$
$\Delta V_{(BR)CES}/\Delta T_J$	Temperature Coeff. of Breakdown Voltage	----	0.30	----	$V/^\circ\text{C}$	$V_{GE} = 0V, I_C = 1.0mA$
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	----	2.5	3.8	V	$I_C = 14A, V_{GE} = 15V$
		----	3.3	----		$I_C = 23A$ See Fig. 2, 5
		----	2.5	----		$I_C = 14A, T_J = 150^\circ\text{C}$
		----	----	----		
$V_{GE(th)}$	Gate Threshold Voltage	3.0	----	5.5		$V_{CE} = V_{GE}, I_C = 250\mu A$
$\Delta V_{GE(th)}/\Delta T_J$	Temperature Coeff. of Threshold Voltage	----	-13	----	$mV/^\circ\text{C}$	$V_{CE} = V_{GE}, I_C = 250\mu A$
g_{fe}	Forward Transconductance ④	3.3	6.5	----	S	$V_{CE} = 100V, I_C = 14A$
I_{CES}	Zero Gate Voltage Collector Current	----	----	250	μA	$V_{GE} = 0V, V_{CE} = 600V$
		----	----	2500		$V_{GE} = 0V, V_{CE} = 600V, T_J = 150^\circ\text{C}$
V_{FM}	Diode Forward Voltage Drop	----	1.4	1.7	V	$I_C = 12A$ See Fig. 13
		----	1.3	1.6		$I_C = 12A, T_J = 150^\circ\text{C}$
I_{GES}	Gate-to-Emitter Leakage Current	----	----	± 100	nA	$V_{GE} = \pm 20V$

	Parameter	Min.	Typ.	Max.	Units	Conditions		
Q_g	Total Gate Charge (turn-on)	----	39	58	nC	$I_C = 14A$		
Q_{ge}	Gate - Emitter Charge (turn-on)	----	8.7	13		$V_{CC} = 400V$		
Q_{gc}	Gate - Collector Charge (turn-on)	----	15	23		See Fig. 8		
$t_{d(on)}$	Turn-On Delay Time	----	67	----	ns	$T_J = 25^\circ C$		
t_r	Rise Time	----	120	----		$I_C = 14A, V_{CC} = 480V$		
$t_{d(off)}$	Turn-Off Delay Time	----	110	170		$V_{GE} = 15V, R_G = 23\Omega$		
t_f	Fall Time	----	94	140	mJ	Energy losses include "tail" and diode reverse recovery.		
E_{on}	Turn-On Switching Loss	----	1.1	----		See Fig. 9, 10, 11, 18		
E_{off}	Turn-Off Switching Loss	----	0.5	----				
E_{ts}	Total Switching Loss	----	1.6	2.4	μs	$V_{CC} = 360V, T_J = 125^\circ C$		
t_{sc}	Short Circuit Withstand Time	10	----	----		$V_{GE} = 15V, R_G = 23\Omega, V_{CPK} < 500V$		
$t_{d(on)}$	Turn-On Delay Time	----	64	----		ns	$T_J = 150^\circ C$, See Fig. 9, 10, 11, 18	
t_r	Rise Time	----	100	----	$I_C = 14A, V_{CC} = 480V$			
$t_{d(off)}$	Turn-Off Delay Time	----	190	----	$V_{GE} = 15V, R_G = 23\Omega$			
t_f	Fall Time	----	180	----	mJ	Energy losses include "tail" and diode reverse recovery.		
E_{ts}	Total Switching Loss	----	2.2	----				
L_E	Internal Emitter Inductance	----	7.5	----		nH	Measured 5mm from package	
C_{ies}	Input Capacitance	----	740	----	pF	$V_{GE} = 0V$		
C_{oes}	Output Capacitance	----	92	----		$V_{CC} = 30V$ See Fig. 7		
C_{res}	Reverse Transfer Capacitance	----	9.4	----		$f = 1.0MHz$		
t_{rr}	Diode Reverse Recovery Time	----	42	60	ns	$T_J = 25^\circ C$ See Fig.	$I_F = 12A$	
		----	80	120		$T_J = 125^\circ C$ 14		
I_{rr}	Diode Peak Reverse Recovery Current	----	3.5	6.0	A	$T_J = 25^\circ C$ See Fig.		$V_R = 200V$
		----	5.6	10		$T_J = 125^\circ C$ 15		
Q_{rr}	Diode Reverse Recovery Charge	----	80	180	nC	$T_J = 25^\circ C$ See Fig.	di/dt = 200A/	
		----	220	600		$T_J = 125^\circ C$ 16		
μs								180
----	A/ μs							120

① Repetitive rating; $V_{GE}=20V$, pulse width limited by max. junction temperature. (See fig. 20)

$T_J = 125^\circ\text{C}$, $V_{CC} = 80\%(V_{CES})$, $V_{GE} = 20\text{V}$, $L = 10\mu\text{H}$, $R_G = 23\Omega$, (See fig. 19) ④ Pulse width $5.0\mu\text{s}$, single shot.

③ Pulse width $\leq 80\mu\text{s}$; duty factor $\leq 0.1\%$.

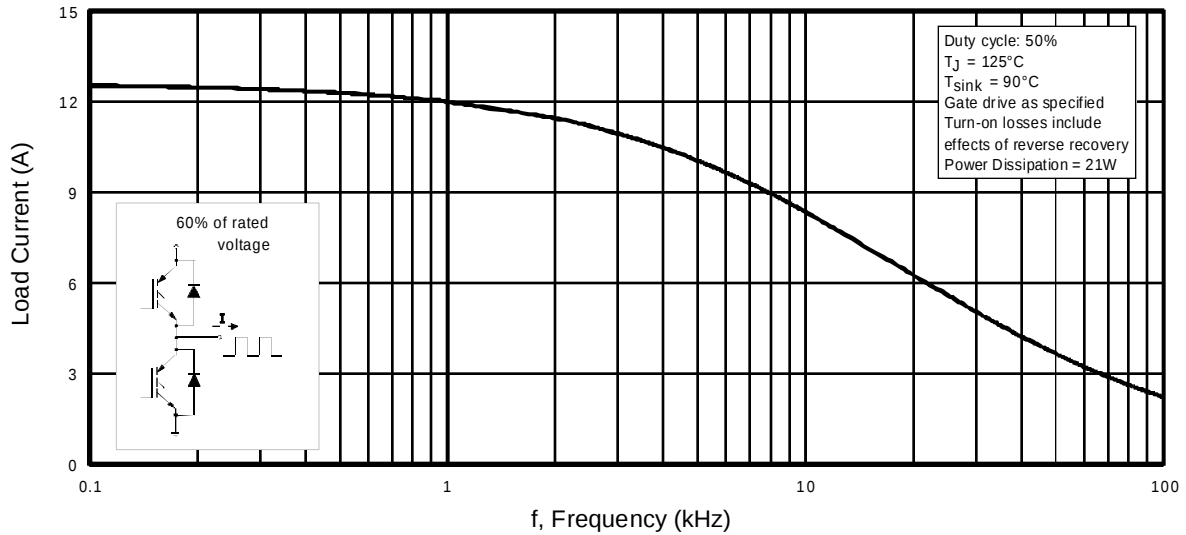


Fig. 1 - Typical Load Current vs. Frequency
 (Load Current = I_{RMS} of fundamental)

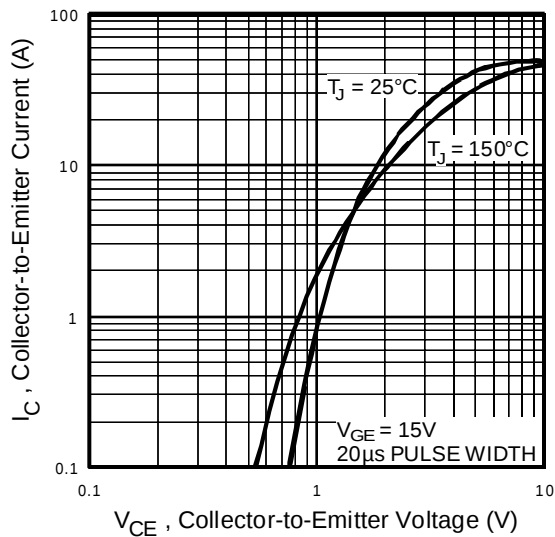


Fig. 2 - Typical Output Characteristics

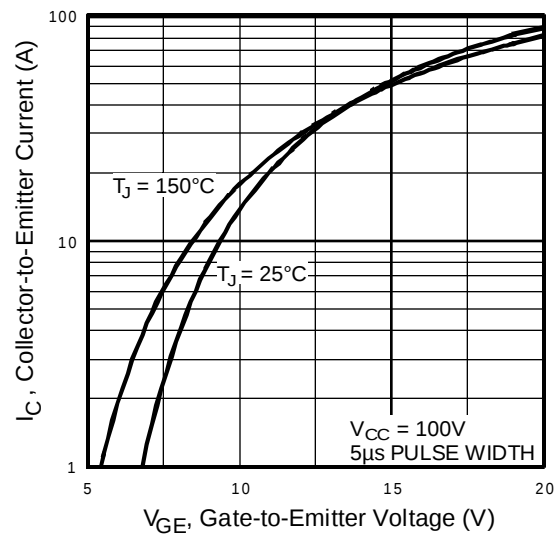


Fig. 3 - Typical Transfer Characteristics

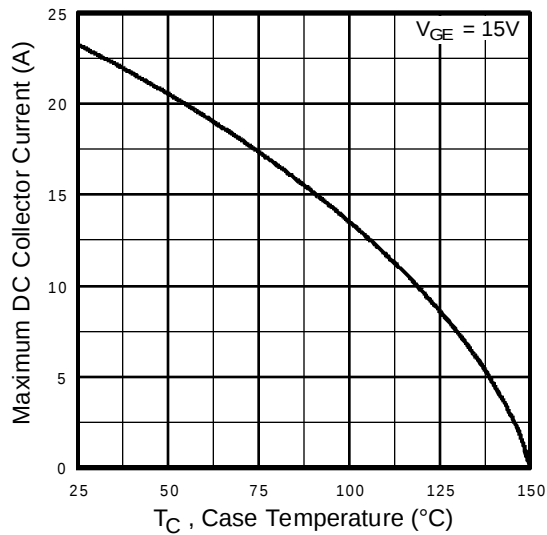


Fig. 4 - Maximum Collector Current vs. Case Temperature

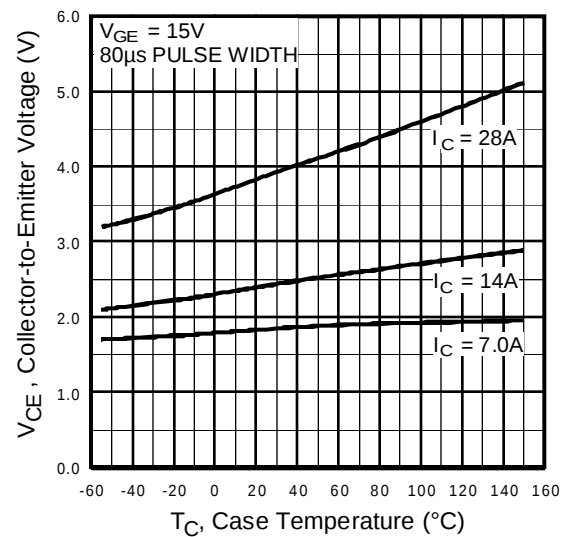


Fig. 5 - Collector-to-Emitter Voltage vs. Case Temperature

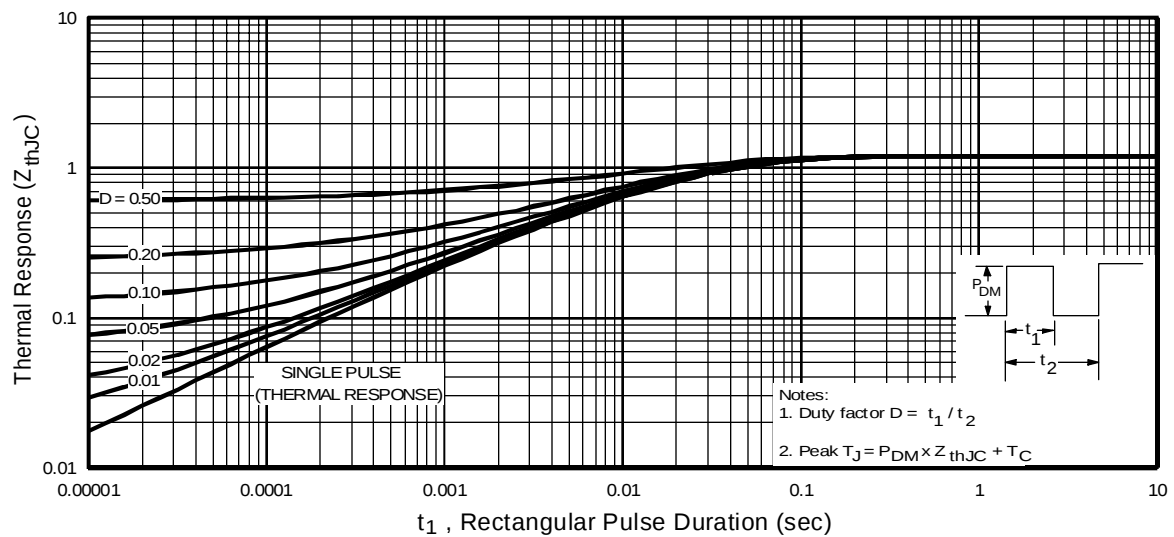


Fig. 6 - Maximum IGBT Effective Transient Thermal Impedance, Junction-to-Case

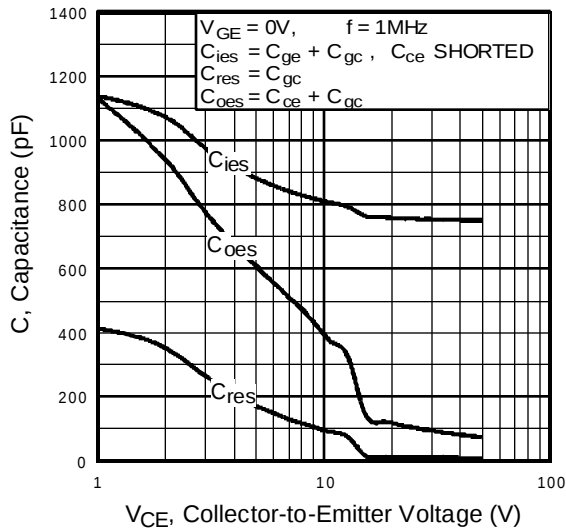


Fig. 7 - Typical Capacitance vs. Collector-to-Emitter Voltage

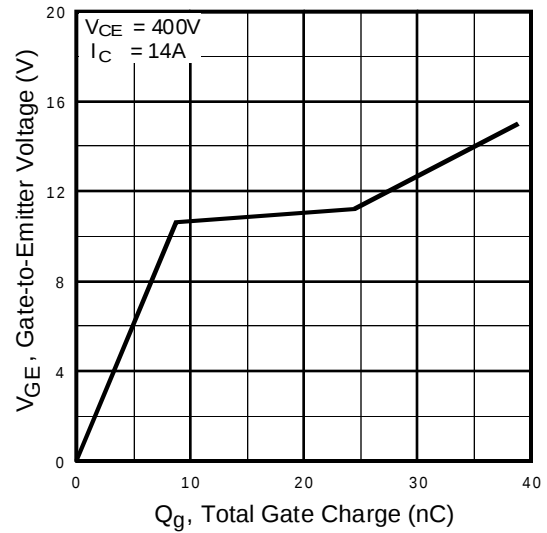


Fig. 8 - Typical Gate Charge vs. Gate-to-Emitter Voltage

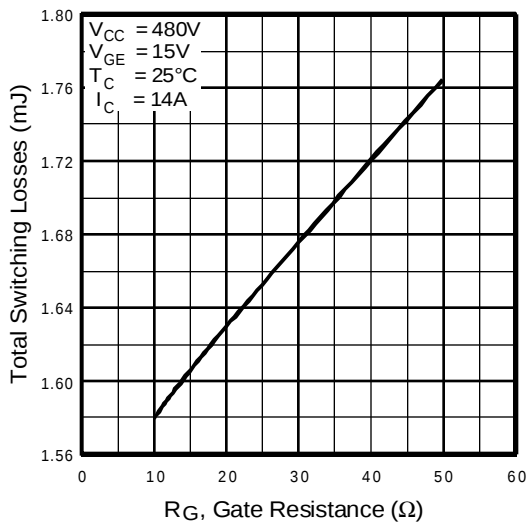


Fig. 9 - Typical Switching Losses vs. Gate Resistance

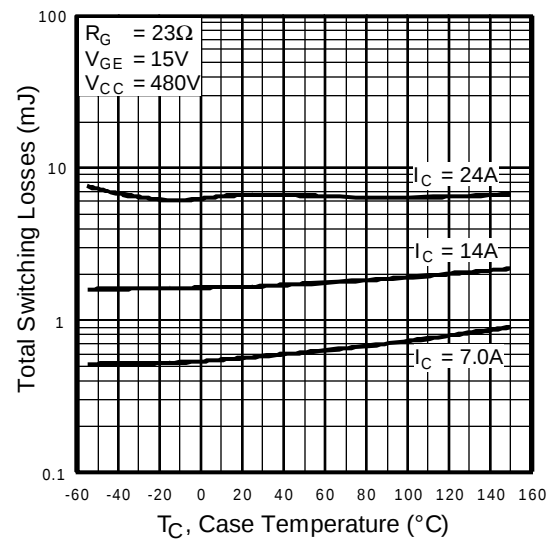


Fig. 10 - Typical Switching Losses vs. Case Temperature

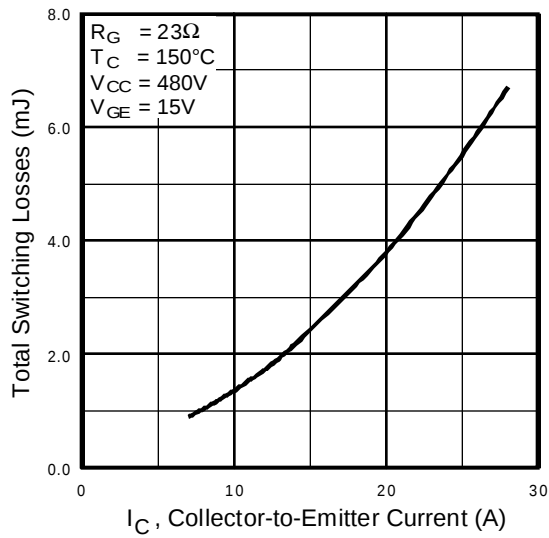


Fig. 11 - Typical Switching Losses vs. Collector-to-Emitter Current

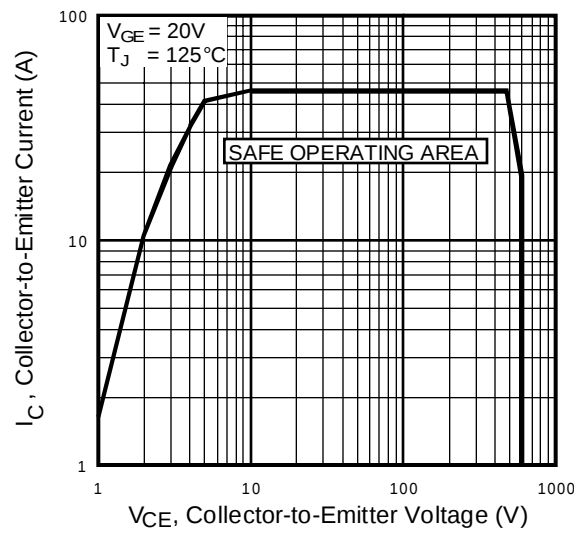


Fig. 12 - Turn-Off SOA

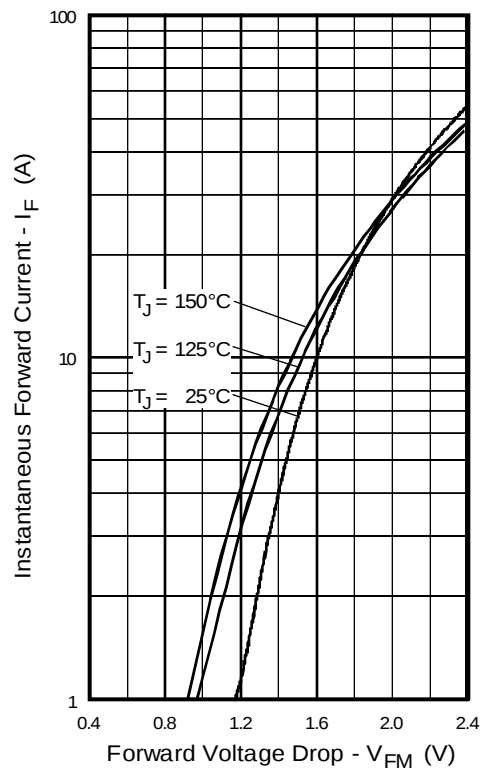
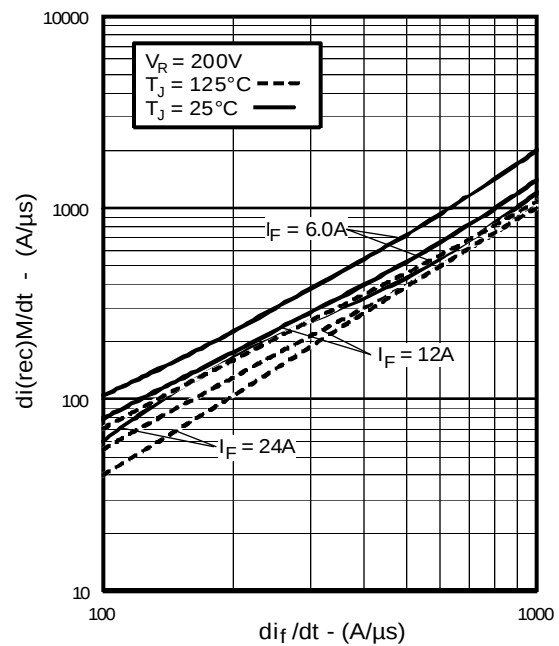
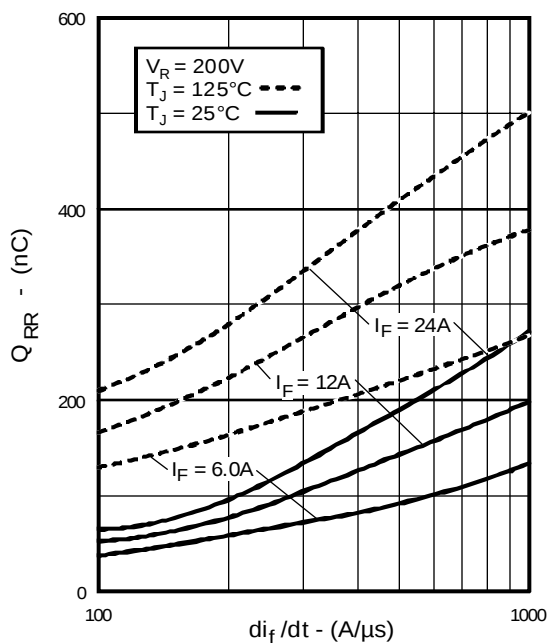
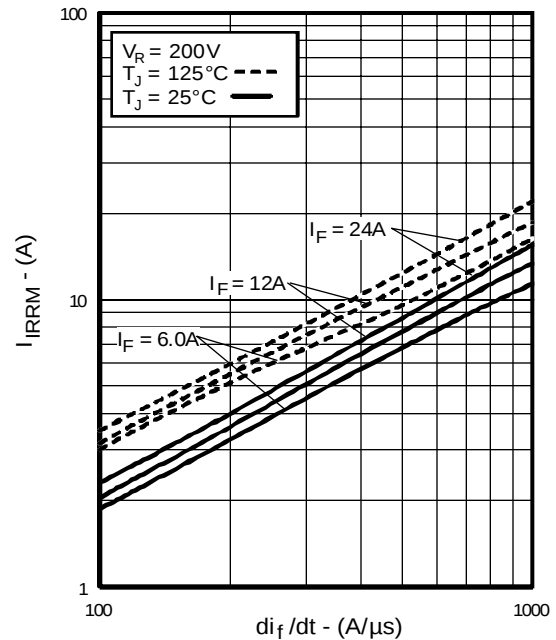
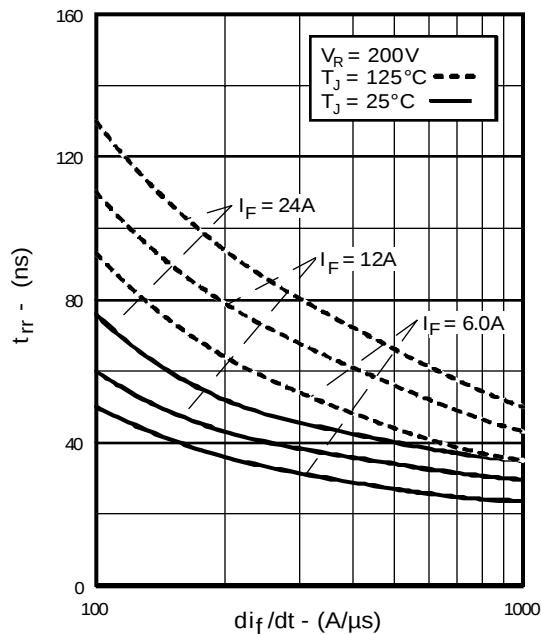


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current



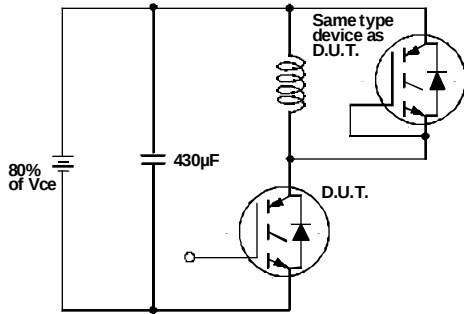


Fig. 18a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off}(\text{diode})$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

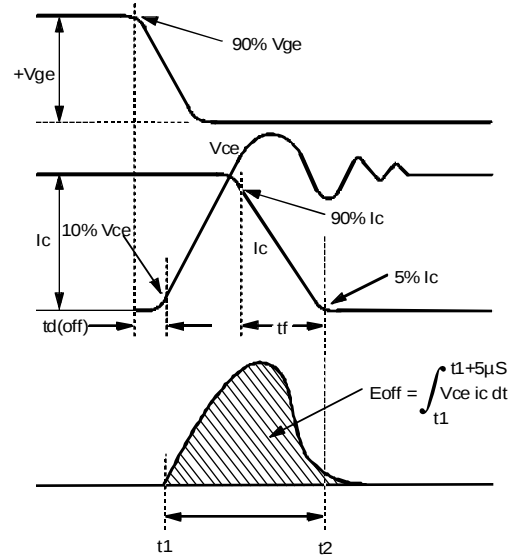


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining E_{off} , $t_{d(off)}$, t_f

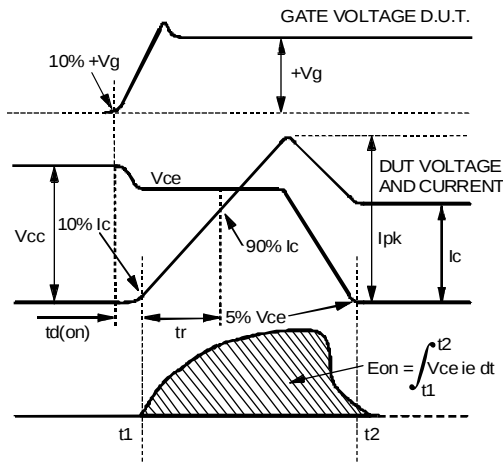


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining E_{on} , $t_{d(on)}$, t_r

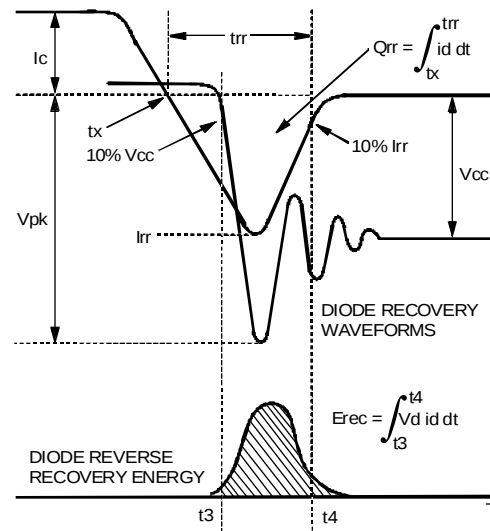


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining E_{rec} , t_{tr} , Q_{rr} , I_{rr}



IRGBC30KD2

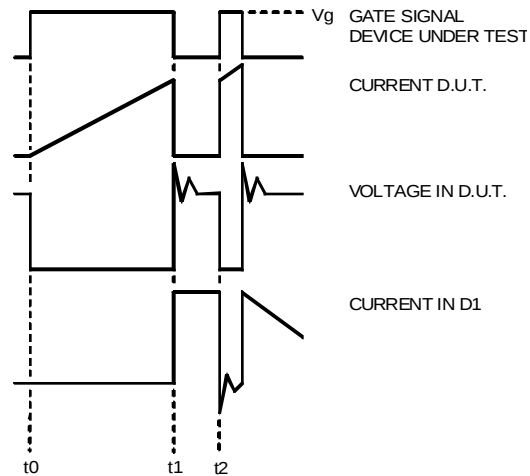


Fig. 18e - Macro Waveforms for Test Circuit of Fig. 18a

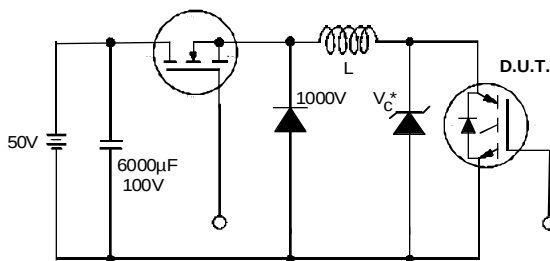


Fig. 19 - Clamped Inductive Load Test Circuit

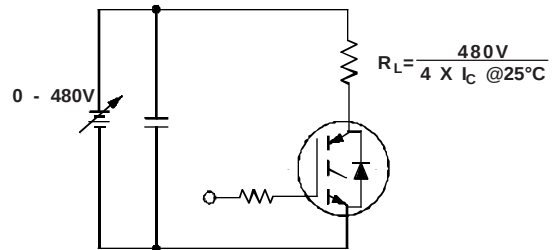
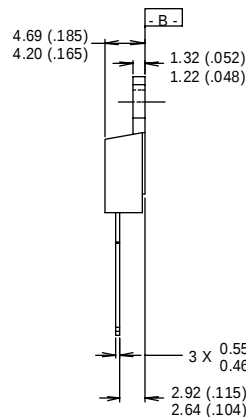
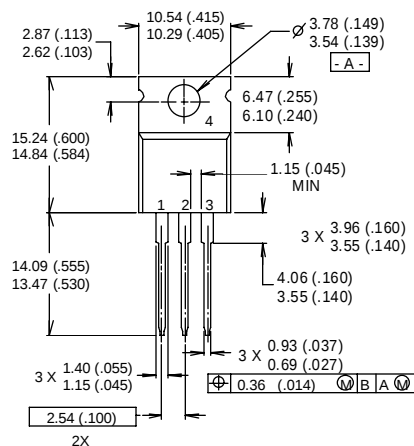


Fig. 20 - Pulsed Collector Current Test Circuit



NOTES:
1 DIMENSIONS & TOLERANCING
PER ANSI Y14.5M, 1982.
2 CONTROLLING DIMENSION : INCH.
3 DIMENSIONS ARE SHOWN
MILLIMETERS (INCHES).
4 CONFORMS TO JEDEC OUTLINE
TO-220AB.

LEAD ASSIGNMENTS
1 - GATE
2 - COLLECTOR
3 - EMITTER
4 - COLLECTOR

CONFORMS TO JEDEC OUTLINE TO-220AB
Dimensions in Millimeters and (Inches)